

LA-UR- 11-02457

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Title: Dislocation Dynamics Model of the Plastic Flow of fcc Polycrystals from Quasi-static to High Strain Rates

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Intended for: JOWOG 32 Materials, LANL, 9-13 May 2011



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Dislocation Dynamics Model of the Plastic Flow of fcc Polycrystals from Quasi-static to High Strain Rates

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ABSTRACT

A new internal state variable model of plastic flow is discussed. The state variables are the mobile and immobile (network) dislocation densities. The model is comprised of three coupled ordinary differential equations: a kinetic equation, which relates the strain rate to the stress, the state variables, the temperature, and the density, and two dislocation evolution equations. The evolution equations account for dislocation generation, storage of dislocations in the network and on grain boundaries, and several dynamic recovery processes. The kinetic equation is not a Van't Hoff-Arrhenius thermal activation model, as is the case for all other rate-dependent strength models, but rather a mean first-passage time model that extends the validity of the kinetic equation to arbitrarily high strain rates. The dislocation recovery processes in the model include mobile-immobile and mobile-mobile annihilation, and single cross-slip plus screw-screw annihilation. Dislocation are generated in the model by Frank-Read sources, the Koehler mechanism (double cross-slip followed by loop/dipole formation), and grain boundary nucleation. Preliminary results on copper deformation are presented.

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JOWOG 32 Materials 2011

***Dean L. Preston
Computational Physics
LANL***

Model overview

- Currently applicable to pure fcc polycrystalline metals

- Two internal state variables

ρ_m – mobile dislocation density

ρ_i – immobile density

- Comprised of 3 coupled ODEs

1. Kinetic equation $\dot{\epsilon}(\sigma, \rho_m, \rho_i, T, P)$

2. Mobile and immobile dislocation evolution equations

$$\dot{\rho}_{m,i} = g_{m,i}(\sigma, \dot{\epsilon}, \rho_m, \rho_i, T, P)$$

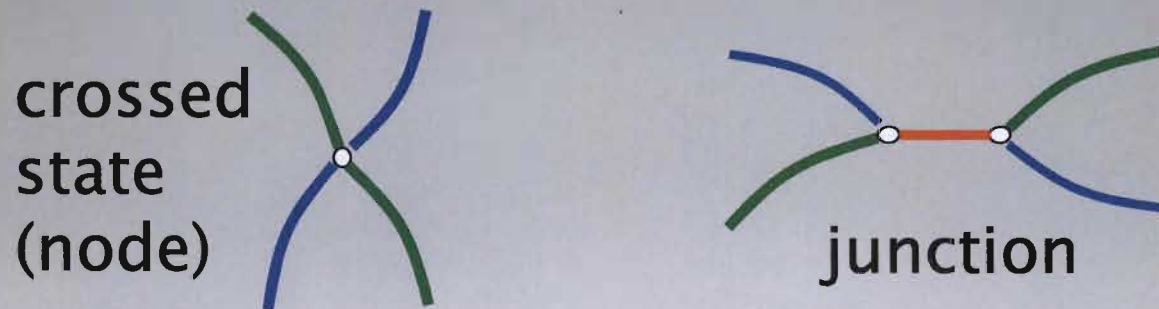
Account for: dislocation generation

network & grain boundary storage

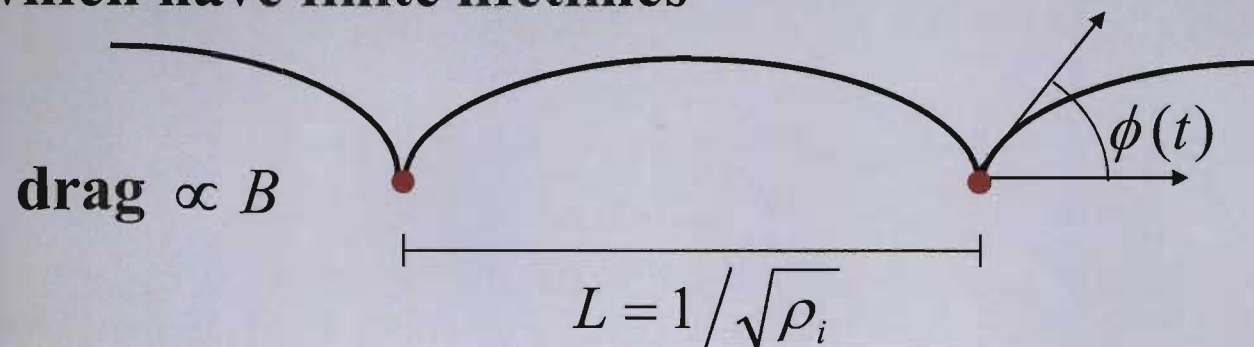
dynamic recovery

Kinetic equation

Rate controlling mechanism is the intersection of attractive, non-coplanar mobile & immobile dislocations



Applied stress bows dislocations between nodes/junctions which have finite lifetimes



High strain rates require MFPT theory

It is generally accepted that the intersection controlled strain rate is related to the stress according to

$$\dot{\epsilon} = \dot{\epsilon}_0 \exp\left\{-\frac{E(\sigma)}{kT}\right\} \quad \text{Van't Hoff-Arrhenius thermal activation (VATA)}$$

but VATA is only valid for $\frac{E(\sigma)}{kT} \gg 1$

$$\text{High } \dot{\epsilon} \Rightarrow \text{large } \sigma \Rightarrow \frac{E(\sigma)}{kT} \ll 1$$

**VATA \rightarrow mean first-passage time (MFPT)
model of dislocation intersection**

**\exists local stress fluctuations at nodes/junctions.
Distribution & correlation time needed for
MFPT calculation.**

- $T = 0$ node/junction dissolution condition $\sigma \geq \sigma_c$

- $T > 0$ $\begin{matrix} \text{local} \\ \text{stress} \\ \text{fluctuation} \end{matrix} + \sigma \geq \sigma_c$ **Fluctuation distribution** is approximated as Gaussian

$$\langle \sigma_{local}^2 \rangle^{1/2} \sim \sqrt{G k T / b^3} \sim \text{rms atomic displacement}$$

Fluctuation correlation time is $\bar{\nu}^{-1}$ $\bar{\nu} =$ avg phonon frequency

MFPT (σ fluctuations) \rightarrow Kinetic Equation

MFPT calculation
specific to dislocation
intersection

$$\longrightarrow t_w = \bar{v}^{-1} \frac{\mathcal{P}}{\ln^2(1 - \mathcal{P})}$$

**mean node/
 junction
 lifetime**

$$\mathcal{P}(\sigma, \rho_i, T, P) = \frac{1}{2} \operatorname{erfc} \left\{ \frac{\kappa b L}{\sqrt{G b k T}} (\sigma_c - \sigma) \right\} \quad L = 1 / \sqrt{\rho_i}$$

$$\sigma_c = \frac{5}{8\pi} \phi_c G \frac{b}{L} \ln \left(\frac{L}{b} \right) \quad \phi_c \approx 1/2 \approx 30^\circ \text{ Cu}$$

**Kinetic
 equation**

$$\dot{\epsilon} = \dot{\epsilon}_0 \left\{ \frac{\ln^2[1 - \mathcal{P}(\sigma)]}{\mathcal{P}(\sigma)} - \frac{\ln^2[1 - \mathcal{P}(-\sigma)]}{\mathcal{P}(-\sigma)} \right\}, \quad \dot{\epsilon}_0 = b \rho_m L \bar{v}$$

Kinetic equation - limits

- $\frac{E(\hat{\sigma}_c - \hat{\sigma})^2}{kT} \gg 1 \quad E = \kappa^2 G b L^2 \quad \hat{\sigma} = \sigma / G$
$$\dot{\epsilon} = \dot{\epsilon}_0 \frac{G}{2\sigma_c} \left(\frac{kT}{\pi E} \right)^{1/2} \exp \left\{ - \frac{E(\hat{\sigma}_c - \hat{\sigma})^2}{kT} \right\}$$

Van't Hoff-Arrhenius exponential with \sqrt{T} pre-factor

- $\sigma \gg \sigma_c \quad \dot{\epsilon} = \dot{\epsilon}_0 \left(\frac{E}{kT} \right)^2 \hat{\sigma}^4$

For $\dot{\epsilon} = \text{const}$ $\sigma \sim T^{1/2} \Rightarrow$ thermal hardening

Dislocation Evolution Equations

$$\dot{\rho}_{m,i} = g_{m,i}(\sigma, \dot{\epsilon}, \rho_m, \rho_i, T, P)$$

NETWORK
STORAGE
= JUNCTION
FORMATION

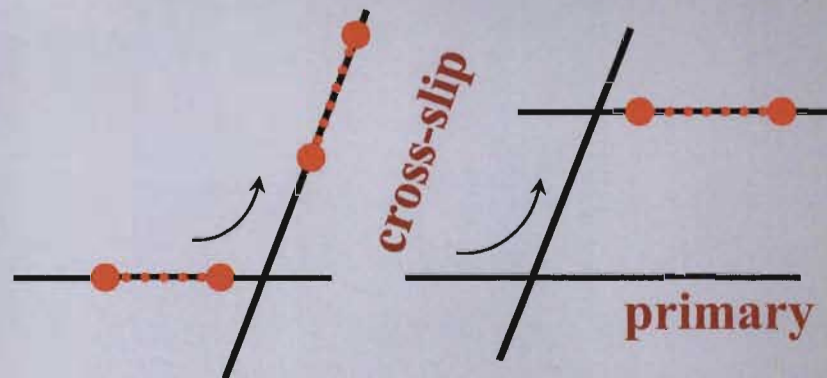
**Storage &
Recovery**

MOBILE--
MOBILE
ANNIHILATION

GRAIN BOUNDARY
STORAGE

MOBILE--
IMMOBILE
ANNIHILATION

CROSS-SLIP + SCREW--
SCREW ANNIHILATION

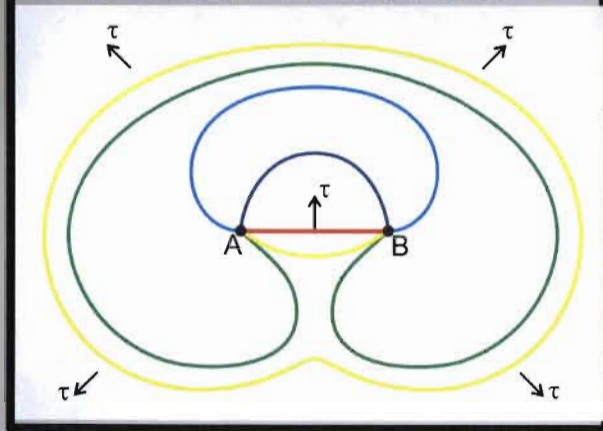


Dislocation Evolution Equations

$$\dot{\rho}_{m,i} = g_{m,i}(\sigma, \dot{\epsilon}, \rho_m, \rho_i, T, P)$$

Generation

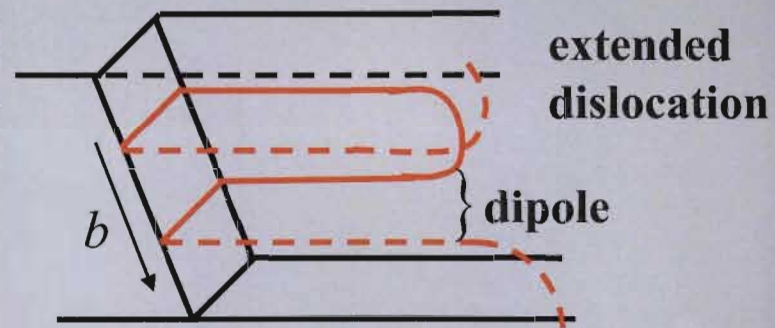
FRANK-READ



GRAIN BOUNDARY NUCLEATION

KOEHLER MECHANISM DOUBLE CROSS-SLIP + LOOP GENERATION

DOUBLE CROSS-SLIP + DIPOLE FORMATION



Network Evolution

$$\begin{aligned}
 \frac{d \rho_i}{d t} = & g_{s\partial} \frac{\dot{\epsilon}}{b D} + (g_{sn} - g_{ami}) \frac{1}{b} \sqrt{\rho_i} \dot{\epsilon} & D = & \text{grain diameter} \\
 & + g_{FR} \frac{D}{b d_{FR}} \dot{\epsilon} \frac{d}{d t} \int_0^{(t-\tau)\theta(t-\tau)} \sqrt{\rho_i(t')} dt' & \tau = & \frac{b D \rho_m}{2 \dot{\epsilon}} \\
 & - g_{ax} \frac{h_c}{b} \rho_i \dot{\epsilon} - g_{tx} \rho_m \bar{v} \exp\{-E_x(\sigma)/kT\} \\
 & + g_{xx} \frac{D}{d_{xx}} \exp\{-E_{xx}(\sigma, 2)/kT\} \bar{v} \frac{d}{d t} \int_0^{t-\tau} \rho_m(t') dt' \\
 & + \frac{2}{\pi} g_{xx} \frac{1}{b d_{xx}} \exp\{-E_{xx}(\sigma, 1)/kT\} \bar{v} \dot{\epsilon} \\
 & \times \frac{d}{d t} \left\{ t^2 \theta(\tau - t) + \tau (t - \tau/2) \theta(t - \tau) \right\} & E_x, E_{xx} = & \text{activation energies}
 \end{aligned}$$

Mobile Dislocation Evolution

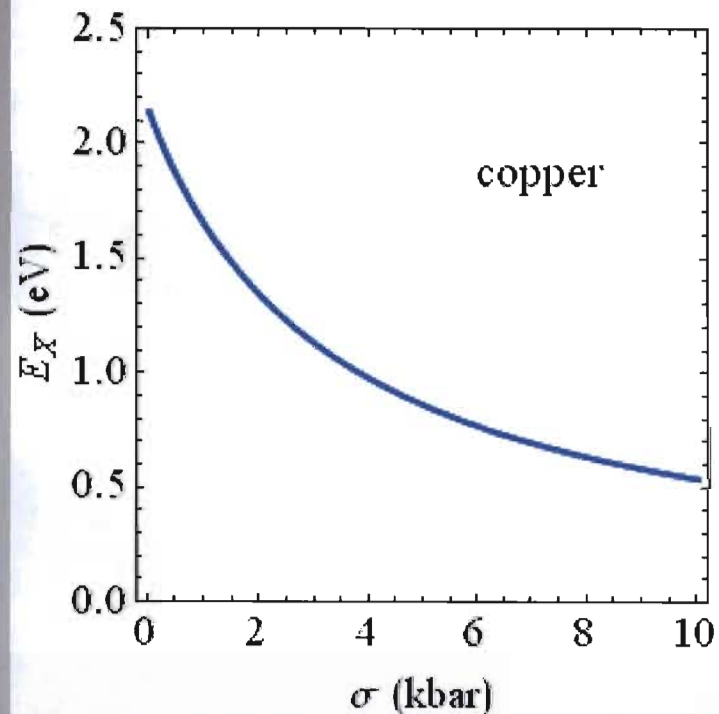
$$\begin{aligned} \frac{d \rho_m}{d t} = & -g_{amm} \frac{1}{b} \sqrt{\rho_m} \dot{\epsilon} - g_{s\partial} \frac{\dot{\epsilon}}{b D} - (g_{sn} + g_{ami}) \frac{1}{b} \sqrt{\rho_i} \dot{\epsilon} \\ & + g_{FR} \frac{D}{b d_{FR} \tau^2} \dot{\epsilon} \frac{d}{d t} \int_{(t-\tau)\theta(t-\tau)}^t (t-t')^2 \sqrt{\rho_i(t')} dt' \\ & - g_{ax} \frac{h_c}{b} \rho_i \dot{\epsilon} - g_{tx} \rho_m \bar{v} \exp\{-E_x(\sigma)/kT\} \\ & + g_{xx} \frac{1}{2b d_{xx}} \exp\{-E_{xx}(\sigma, 2)/kT\} \bar{v} \dot{\epsilon} \frac{d}{d t} \{t^2 \theta(\tau-t) + \tau^2 \theta(t-\tau)\} \end{aligned}$$

**cross-slip
terms**

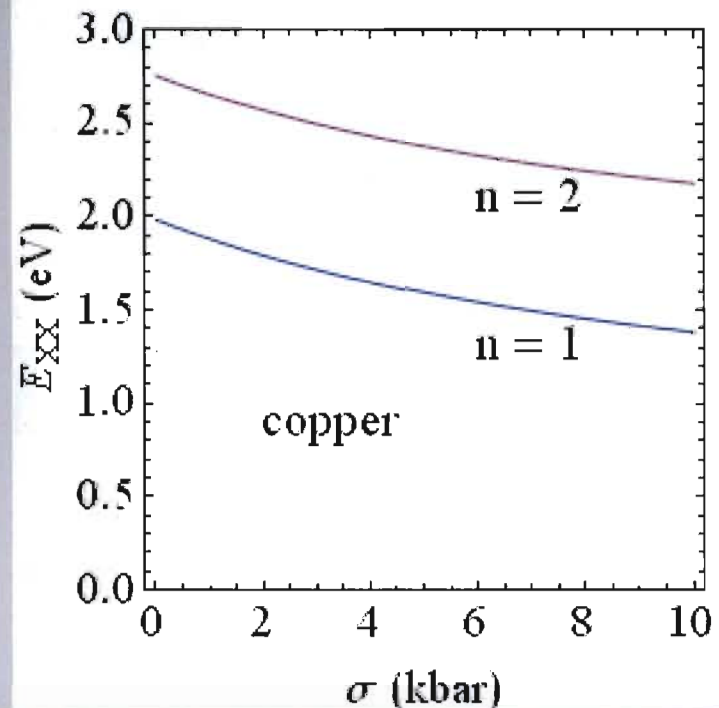
$$\frac{d \rho_{m,i}^{x,xx}}{d \epsilon} \sim \frac{\bar{v}}{\dot{\epsilon}} \exp\left\{-\frac{E_{x,xx}}{kT}\right\}$$

**cross-slip
enhanced
at high T
& low rates**

Single & double cross-slip activation energies



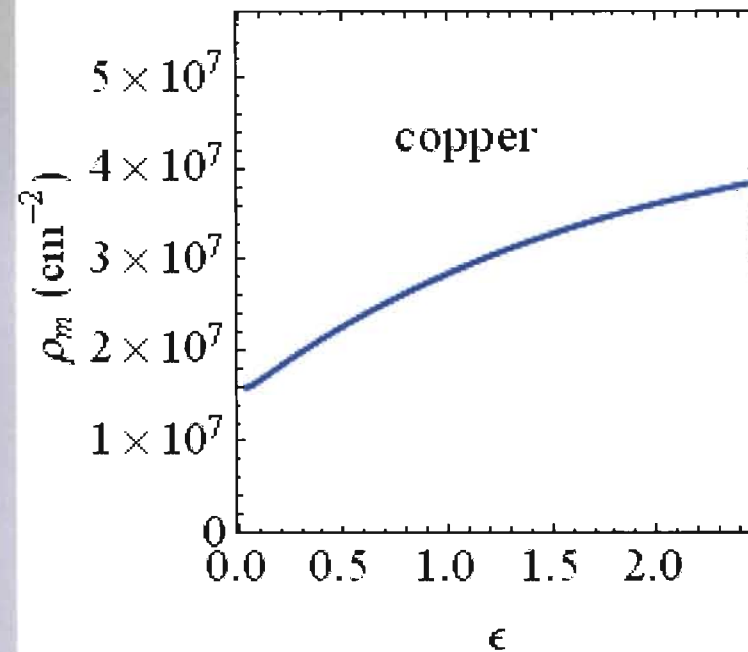
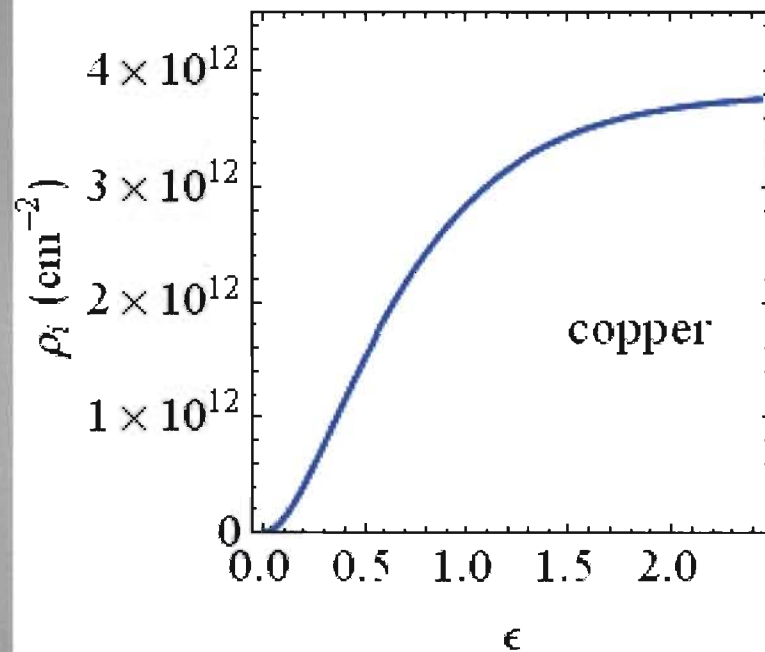
**Single cross-slip:
modified Friedel-Escaig**



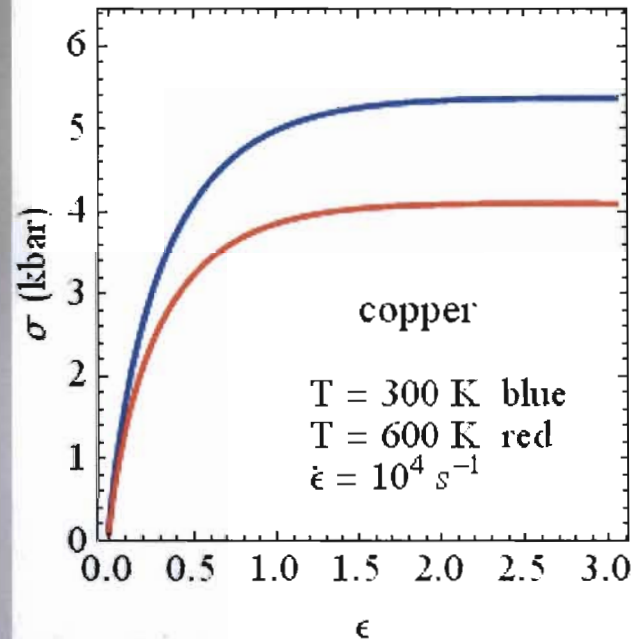
**Double cross-slip:
extended Friedel-Escaig**

Preliminary results on Cu

Low T: cross-slip not exercised

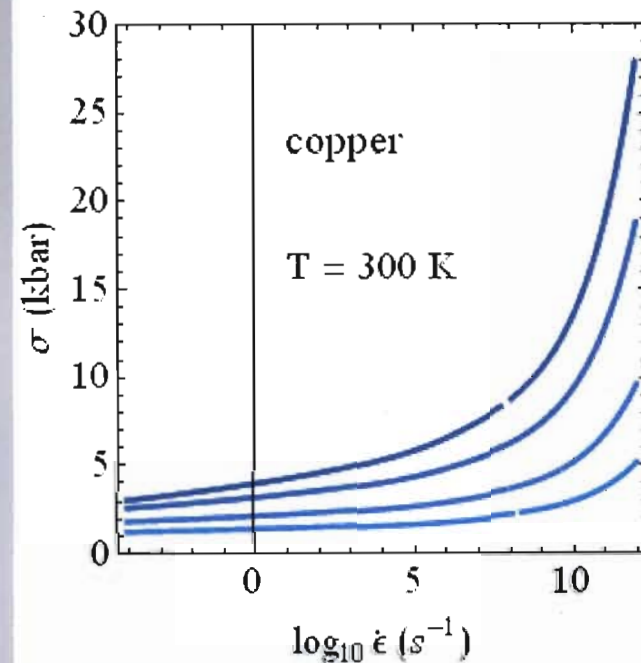


Preliminary results on copper



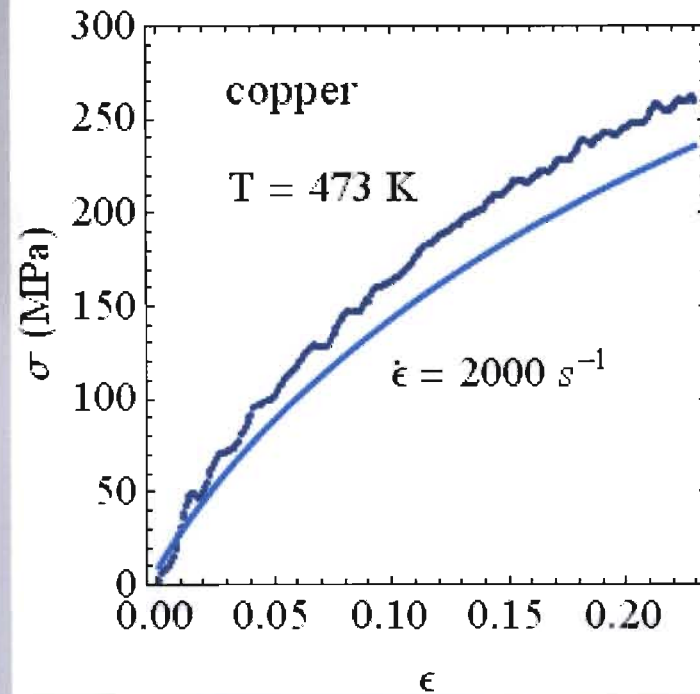
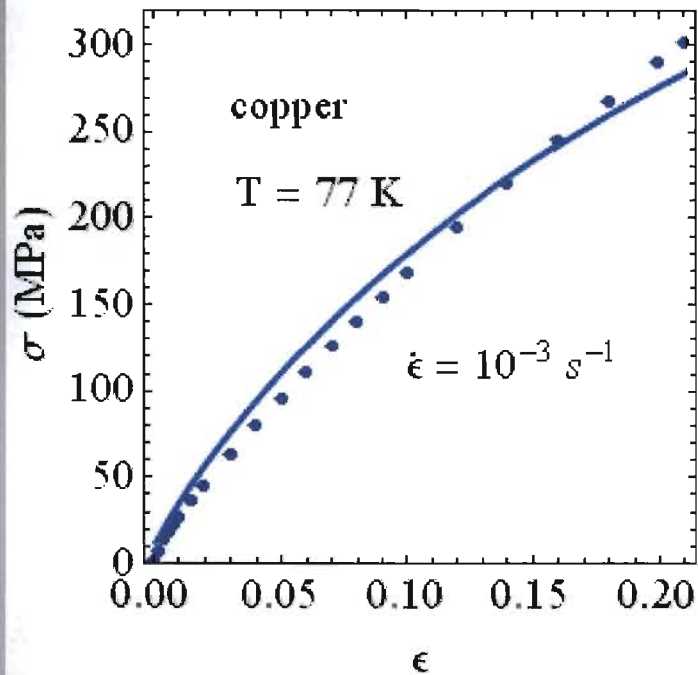
Thermal softening is due to T-dependence of mobile-immobile interactions

Flow stress vs rate for strains 0.1, 0.2, 0.5, $\epsilon \gg 1$



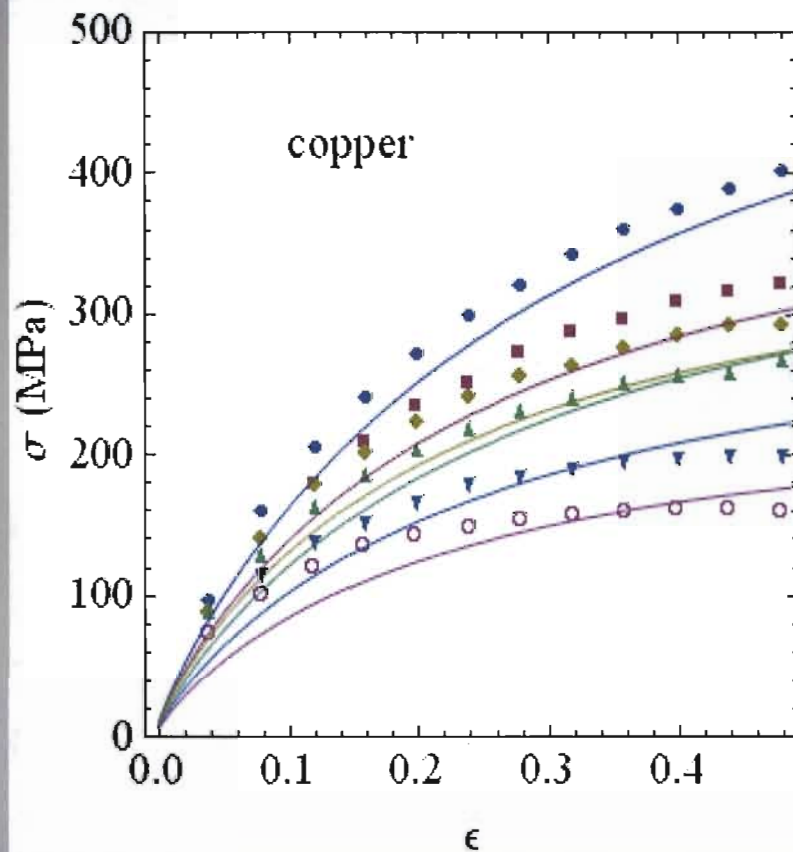
Increase in rate sensitivity not due to dislocation drag

Stress-strain: model vs data on OFE copper



Did not optimize parameter values

Comparison with PTW model



solid circles: 298 K, 2000 s⁻¹

squares: 298 K, 0.1 s⁻¹

diamonds: 298 K, 0.001 s⁻¹

up triangles: 673 K, 2000 s⁻¹

down triangles: 873 K, 2000 s⁻¹

open circles: 1073 K, 2000 s⁻¹

Future Directions

- **Cu model: turn on cross-slip**
- **Include dislocation drag ➤ phonon drag, flutter, ...**
- **Account for dependence of strength on material density**
 - **Investigate shear modulus scaling**
 $\sigma(\dots, \rho) / G(\rho, T)$ is assumed independent of density
- **Compute fraction of plastic work dissipated (usually taken to be 100%)**
- **Calculate dislocation cell formation due to mesoscale stress fluctuations**
- **May be necessary to “model the model”**